

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	,		, 0--	2450.000, 0	7.85	1.84	39.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2178	HBBL-600-10000 Charge:xxxx, 2024-Jan-15	EX3DV4 - SN7383, 2023-06-05	DAE3 Sn427, 2023-05-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-01-15, 08:35	2024-01-15, 08:45
psSAR1g [W/kg]	13.7	13.6
psSAR10g [W/kg]	6.21	6.32
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		9.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

